CSE635, Assignment 3, Main Memory, and Virtual Memory

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1-Bit Latch

Test Strategy

D	Clk	q	qbar	comment
1	1	1	0	problem reacting to change in D
1	0	1	0	The latch does not hold D
0	1	0	1	Deasserting D (do latch depend on clk?)
1	0	0	1	output is not changing at the clock

Test Output

```
Time is now: 15 ns, D=1, clk=1, Actual q=1, Actual nq=0 Test PASSED Time is now: 30 ns, D=1, clk=0, Actual q=1, Actual nq=0 Test PASSED Time is now: 45 ns, D=0, clk=1, Actual q=0, Actual nq=1 Test PASSED Time is now: 60 ns, D=1, clk=0, Actual q=0, Actual nq=1 Test PASSED
```

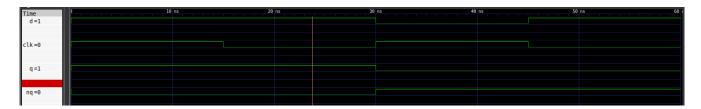


Figure 1: 1-bit Latch

Address Decoder 2

Test Strategy

address	decode	comment
7	10	Corner case for first case.
15	01	Corner case for second case (changing both bits).
17	01	does save the output (out side the range behaviour).
20	11	problem reacting to change in D.

Test Output

```
Time is now: 15 ns, address=7, decode=10, Actual decode=10 Test PASSED Time is now: 30 ns, address=15, decode=01, Actual decode=01 Test PASSED Time is now: 45 ns, address=17, decode=01, Actual decode=01 Test PASSED Time is now: 60 ns, address=20, decode=11, Actual decode=11 Test PASSED
```



Figure 2: Address Decoder $_2$

Mux

Test Strategy

abcd	\mathbf{S}	\mathbf{Z}	comment
0001	11	1	Not selecting the last input.
0001	00	0	stuck at 1 output.
1000	00	1	not selecting first input.
0010	10	1	Not selecting third input.
1000	01	0	stuck at 1 fault.
1100	01	1	Not selecting second input.

Test Output

```
Time is now: 15 ns, a,b,c,d=0001, s=11, z=1, Actual z=1 Test PASSED Time is now: 30 ns, a,b,c,d=0001, s=00, z=0, Actual z=0 Test PASSED Time is now: 45 ns, a,b,c,d=1000, s=00, z=1, Actual z=1 Test PASSED Time is now: 60 ns, a,b,c,d=0010, s=10, z=1, Actual z=1 Test PASSED Time is now: 75 ns, a,b,c,d=1000, s=01, z=0, Actual z=0 Test PASSED Time is now: 90 ns, a,b,c,d=1100, s=01, z=1, Actual z=1 Test PASSED
```

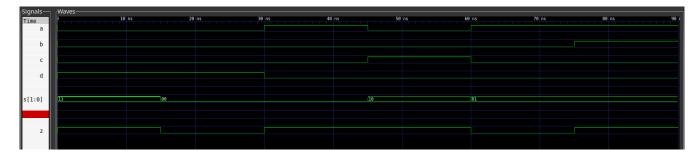


Figure 3: Mux simulation

ALU

Test Strategy

op	a	b	c	comment
	1100	1101	1111	11 4 4
01	1100	1101	1111	all ones test.
01	0011	1100	0111	maximum range(positive) of c.
01	1111	0111	1000	maximum range (negative) of c.
01	0011	0011	0000	getting zero output.
00	1100	1101	1001	random test.
00	0011	1100	1111	all ones test of c.
00	1111	1001	1000	maximum range (negative) of c.
00	0011	0100	0111	maximum range(positive) of c.
00	0011	1101	0000	getting zero output.
10	0011	1111	1101	not changing op.
10	0111	0001	0111	max range(positive).
10	1100	0010	1000	max range(negative).
10	1101	1110	0110	not considering sign.
11	1101	1110	0000	not considering sign.
11	0111	0001	0111	max range(positive).
11	1000	0001	1000	max range(negative).
11	0111	1101	1110	random example.

Test output

```
time is now: 15 ns, op=sub, a=1100, b=1101, c=-1, actual c=1111 test passed time is now: 30 ns, op=sub, a=0011, b=1100, c=7, actual c=0111 test passed time is now: 45 ns, op=sub, a=1111, b=0111, c=-8, actual c=1000 test passed time is now: 60 ns, op=sub, a=0011, b=0011, c=0, actual c=0000 test passed time is now: 75 ns, op=add, a=1100, b=1101, c=-7, actual c=1001 test passed time is now: 90 ns, op=add, a=0011, b=1100, c=-1, actual c=1111 test passed time is now: 105 ns, op=add, a=1111, b=1001, c=-8, actual c=1000 test passed time is now: 120 ns, op=add, a=0011, b=0100, c=7, actual c=0111 test passed time is now: 135 ns, op=add, a=0011, b=1101, c=0, actual c=0000 test passed
```

```
time is now: 150 ns, op=mul, a=0011, b=1111, c=-3, actual c=1101 test passed time is now: 165 ns, op=mul, a=0111, b=0001, c=7, actual c=0111 test passed time is now: 180 ns, op=mul, a=1100, b=0010, c=-8, actual c=1000 test passed time is now: 195 ns, op=mul, a=1101, b=1110, c=6, actual c=0110 test passed time is now: 210 ns, op=div, a=1101, b=1110, c=1, actual c=0000 failed, error messages: not considering sign.

time is now: 225 ns, op=div, a=0111, b=0001, c=7, actual c=0111 test passed time is now: 240 ns, op=div, a=1000, b=0001, c=-8, actual c=1000 test passed time is now: 255 ns, op=div, a=0111, b=1101, c=-2, actual c=1110 test passed
```

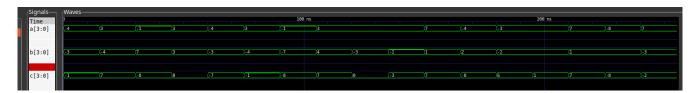


Figure 4: ALU

RAM single port

Test strategy

rw	enable	address	datain	dataout	comment
1	1	0000	1100	0000	memory is not storing input.
0	1	0000	1100	1100	memory is not storing input.
1	1	1000	0101	1100	stuck at the previous output.
0	1	1000	0101	0101	stuck at the previous output.
0	1	0000	1100	1100	loses the stored data.
0	0	1000	0101	0101	Enable is now working.
1	1	1111	1101	1100	corner cases (last address).
0	1	1111	1101	1101	corner cases (last address).
1	1	1100	1000	1000	corner cases (middle address).
0	1	1100	1000	1000	corner cases (middle address).
0	1	0000	1100	1100	Not storing previous data.
1	1	1000	1111	1111	Not accepting new data.
0	1	1000	1111	1111	Not accepting new data.

Test Output

```
Time is now: 30 ns, rw=1, enable=1, address=0000, write_data_in=1100, read_data_out=0000, memory data=1100

Time is now: 45 ns, rw=0, enable=1, address=0000, write_data_in=1100, read_data_out=1100, memory data=1100 Test PASSED

Time is now: 60 ns, rw=1, enable=1, address=1000, write_data_in=0101, read_data_out=1100, memory data=0101

Time is now: 75 ns, rw=0, enable=1, address=1000, write_data_in=0101, read_data_out=0101, memory data=0101 Test PASSED

Time is now: 90 ns, rw=0, enable=1, address=0000, write_data_in=1100, read_data_out=1100, memory data=1100 Test PASSED

Time is now: 105 ns, rw=0, enable=0, address=1000, write_data_in=0101, read_data_out=0101, memory data=ZZZZ Test PASSED

Time is now: 120 ns, rw=1, enable=1, address=1111, write_data_in=1101, read_data_out=1100, memory data=1101

Time is now: 135 ns, rw=0, enable=1, address=1111, write_data_in=1101,
```

```
read_data_out=1101, memory data=1101 Test PASSED

Time is now: 150 ns, rw=1, enable=1, address=1100, write_data_in=1000, read_data_out=1000, memory data=1000

Time is now: 165 ns, rw=0, enable=1, address=1100, write_data_in=1000, read_data_out=1000, memory data=1000 Test PASSED

Time is now: 180 ns, rw=0, enable=1, address=0000, write_data_in=1100, read_data_out=1100, memory data=1100 Test PASSED

Time is now: 195 ns, rw=1, enable=1, address=1000, write_data_in=1111, read_data_out=1111, memory data=1111

Time is now: 210 ns, rw=0, enable=1, address=1000, write_data_in=1111, read_data_out=1111, memory data=1111 Test PASSED
```



Figure 5: RAM single port

Ram Dual Port

Test Strategy

r	w	address_in	address_out	data_in	data_out	
1	1	0000	0000	1100	1100	Reading and writing at the same time.
1	1	1101	1101	0101	0101	Reading and writing at the same time.
1	0	1101	1101	1111	0101	writing when ever address is valid.
1	1	1001	1101	1111	0101	writing and reading in different locations.
1	0	1001	1001	1111	1111	Reading the previous location.
1	1	0000	1101	1000	0101	Not accepting multiple writes to the same location.
1	0	0000	0000	1000	1000	Not accepting multiple writes to the same location.
0	0	0000	0000	1101	1000	read and write stuck at 0.
1	0	0000	0000	1000	1000	read and write stuck at 0.

Test Output

```
Time is now: 30 ns, r=1, w=1, address_in=0000, address_out=0000,
data_in=1100, data_out=1100 Test PASSED
Time is now: 45 ns, r=1, w=1, address_in=1101, address_out=1101,
data_in=0101, data_out=0101 Test PASSED
Time is now: 60 ns, r=1, w=0, address_in=1101, address_out=1101,
data in=1111, data out=0101 Test PASSED
Time is now: 75 ns, r=1, w=1, address_in=1001, address_out=1101,
data_in=1111, data_out=0101 Test PASSED
Time is now: 90 ns, r=1, w=0, address_in=1001, address_out=1001,
data_in=1111, data_out=1111 Test PASSED
Time is now: 105 ns, r=1, w=1, address_in=0000, address_out=1101,
data_in=1000, data_out=0101 Test PASSED
Time is now: 120 ns, r=1, w=0, address_in=0000, address_out=0000,
data_in=1000, data_out=1000 Test PASSED
Time is now: 135 ns, r=0, w=0, address_in=0000, address_out=0000,
data_in=1101, data_out=1000 Test PASSED
Time is now: 150 ns, r=1, w=0, address_in=0000, address_out=0000,
```

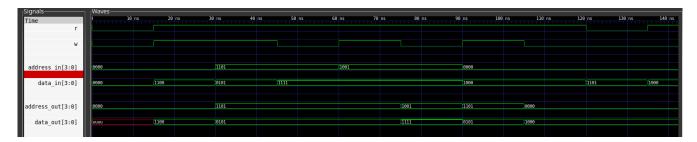


Figure 6: RAM dual port

ROM

Test strategy

enable	address	data	comment
1	000	000000	initial value.
1	111	110001	data stuck at 0.
1	010	000100	data stuck at 1.
1	110	100100	Random test.
0	110	100100	disable the rom destroys data.
1	101	011001	ROM is now working after enable.

Test Output

```
Time is now: 30 ns, enable=1, address=000, Actual data=000000, data=000000 Test PASSED Time is now: 45 ns, enable=1, address=111, Actual data=110001, data=110001 Test PASSED Time is now: 60 ns, enable=1, address=010, Actual data=000100, data=000100 Test PASSED Time is now: 75 ns, enable=1, address=110, Actual data=100100, data=100100 Test PASSED Time is now: 90 ns, enable=0, address=110, Actual data=100100, data=ZZZZZZZ Test PASSED Time is now: 105 ns, enable=1, address=101, Actual data=011001, data=011001 Test PASSED
```



Figure 7: ROM

Shift Register

Test strategy

clk	clr	l_in	r_in	s0	s1	d	q	comment
1	1	0	0	1	1	1111	1111	stuck at 0 output.
0	1	0	0	1	0	1111	1111	stuck at 1 output.
1	1	0	0	1	0	1111	1110	stuck at 1 output.
0	1	0	0	1	0	1111	1110	Not shifting left.

$\overline{\operatorname{clk}}$	clr	l_in	r_in	s0	s1	d	q	comment
1	1	0	0	1	0	1111	1100	Not shifting left.
0	1	0	1	1	0	1111	1100	r_in stuck at 0.
1	1	0	1	1	0	1111	1001	r_in stuck at 0.
0	1	0	1	0	1	1111	1001	stuck at shifting left state.
1	1	0	1	0	1	1111	0100	stuck at shifting left state.
0	1	1	1	0	1	1111	0100	l_in stuck at 0.
1	1	1	1	0	1	1111	1010	l_in stuck at 0.
1	0	1	1	0	1	1111	0000	Not clearing the output.
0	1	1	1	0	1	1111	0000	random test after clear.
1	1	1	1	0	1	1111	1000	random test after clear.

Test output

Time is now: 30 ns, clk=1, clr=1, l_in=0, r_in=0, s0=1, s1=1, d=1111, Actual q=1111 , q=1111 Test PASSED Time is now: 45 ns, clk=0, clr=1, l_in=0, r_in=0, s0=1, s1=0, d=1111, Actual q=1111, q=1111 Test PASSED Time is now: 60 ns, clk=1, clr=1, l_in=0, r_in=0, s0=1, s1=0, d=1111, Actual q=1110, q=1110 Test PASSED Time is now: 75 ns, clk=0, clr=1, l in=0, r in=0, s0=1, s1=0, d=1111, Actual q=1110, q=1110 Test PASSED Time is now: 90 ns, clk=1, clr=1, l_in=0, r_in=0, s0=1, s1=0, d=1111, Actual q=1100, q=1100 Test PASSED Time is now: 105 ns, clk=0, clr=1, l_in=0, r_in=1, s0=1, s1=0, d=1111, Actual q=1100, q=1100 Test PASSED Time is now: 120 ns, clk=1, clr=1, l_in=0, r_in=1, s0=1, s1=0, d=1111, Actual q=1001, q=1001 Test PASSED Time is now: 135 ns, clk=0, clr=1, l_in=0, r_in=1, s0=0, s1=1, d=1111, Actual q=1001, q=1001 Test PASSED Time is now: 150 ns, clk=1, clr=1, l_in=0, r_in=1, s0=0, s1=1, d=1111, Actual q=0100, q=0100 Test PASSED Time is now: 165 ns, clk=0, clr=1, l_in=1, r_in=1, s0=0, s1=1, d=1111, Actual q=0100, q=0100 Test PASSED Time is now: 180 ns, clk=1, clr=1, l_in=1, r_in=1, s0=0, s1=1, d=1111, Actual q=1010, q=1010 Test PASSED Time is now: 195 ns, clk=1, clr=0, l_in=1, r_in=1, s0=0, s1=1, d=1111, Actual q=0000, q=0000 Test PASSED Time is now: 210 ns, clk=0, clr=1, l_in=1, r_in=1, s0=0, s1=1, d=1111, Actual q=0000, q=0000 Test PASSED Time is now: 225 ns, clk=1, clr=1, l_in=1, r_in=1, s0=0, s1=1, d=1111, Actual q=1000, q=1000 Test PASSED

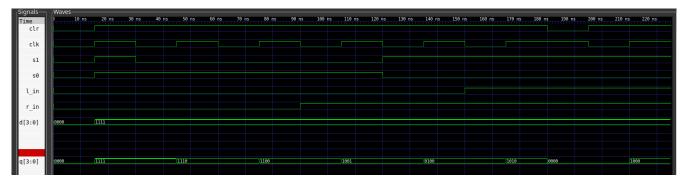


Figure 8: Shift Register